

TUESDAY

	08:00	Get Together
	08:45	Official opening
FIB Tomography	Inv 1	09:00 FIB-SEM reveals that flagellum construction is an early event in the life cycle of <i>Trypanosoma brucei</i> <i>Moara LEMOS - Institut Pasteur - Paris France</i>
	Talk 1	09:30 3D Tomography On UO2 Irradiated Fuel <i>Thierry BLAY - CEA Cadarache France</i>
	Talk 2	09:50 3D HR-EBSO Examination of Deformed W Micro-cantilevers <i>Szilvia KALACSKA - Empa Swiss Federal Laboratories for Materials and Technology Thun Switzerland</i>
Exi 1	10:10 New 3D developments of the JEOL JIB-4700F <i>Guillaume BRUNETTI - JEOL France</i>	
	10:30	COFFEE BREAK
TEM Sample Preparation	Talk 3	11:00 Development of FIB sample preparation method for in-situ biasing of conductive bridge resistive memory devices in the TEM <i>Remy BERTHER - CEA LETI Grenoble France</i>
	Talk 4	11:20 New level of control and automation for SEM and FIB with Python scripting interface <i>Anna PROKHODTSEVA - ThermoFisher Scientific</i>
	Exi 2	11:40 New Generation of Plasma FIB is Coming – Introduction of i-FIB+ Column and its Innovative Control <i>Tamas HRVAC - TESCAN Brno Czech Republic</i>
Talk 5	12:00 FIB-micro-cleavage, a new technique for high quality sample preparation in transmission electron microscopy <i>Jean Luc ROUVIERE - CEA INAC Grenoble France</i>	
	12:20	LUNCH + POSTER
Tutorial 1	Tuto 1	14:00 From source to sample: ion optics <i>Ray HILL - Carl ZEISS Microscopy Peabody USA</i>
	Exi 3	14:30 A Multi-Step Approach for Material Characterization by a Triple-Beam FIB-SEM System NX5000 <i>Felix VON CUBE - Hitachi High-Technologies Krefeld Germany</i>
	Tuto 2	14:50 FIB Patterning Strategies: Optimizing Scanning Parameters for Direct and Gas Assisted Patterning <i>Ken LAGAREC - Fibics Incorporated Ottawa Canada</i>
	15:20	COFFEE BREAK
Application cases	Talk 6	15:50 FIB-DIC Technique for Residual Stress Evaluation at the Micro and Nanoscale <i>Hiri DLUHOS - TESCAN Brno Czech Republic</i>
	Exi 4	16:10 ACT - Anti Curtaining Table for Smooth Cross Sections on Difficult Materials <i>Andrew SMITH - Kleindiek Nanotechnik Reutlingen Germany</i>
	Talk 7	16:30 FIB use in the semiconductor industry : a versatile multi-purpose technique <i>Fredéric LORUT - ST Microelectronics Crolles France</i>
Exi 5	16:50 Advanced FIB-SEM Nanofabrication employing a FIB-centric, Lithography System and Multi-Ion Species Platform <i>Sven BAUERDICK - Raith GmbH Dortmund Germany</i>	
	17:10	Walk to Aperitif + Gala Dinner

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Microscopy GmbH



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WEDNESDAY

	09:00	Get Together
FIB structuring	Inv 2	09:30 Focused-ion-beam induced deposition (FIBID) <i>Jose M. DE TERESA - CSIC-University of Zaragoza Spain</i>
	Talk 8	10:00 Self-forming Superconducting Microstructures from Weyl-Semimetals <i>Maja BACHMANN - Max Planck Institute for Chemical Physics of Solids Dresden Germany</i>
	Exi 6	10:20 FIB Automation For TEM Prep and Tool Maintenance <i>Valerie BROGDEN - ThermoFisher Scientific Eindhoven The Netherlands</i>
Talk 9	10:40 Focused Ion Beam in Quantum Matter Science <i>Philip MOLL - EPFL Lausanne Switzerland</i>	
	11:00	COFFEE BREAK
FIB analytics	Talk 10	11:10 Innovative methodology of increasing FIB-TOF-SIMS signals during elemental characterization in negative ion detection mode <i>Agnieszka PRIEBE - Empa Swiss Federal Laboratories for Materials and Technology Thun Switzerland</i>
	Talk 11	11:30 Application of FIB-SEM based ToF-SIMS to Geoscience Research <i>William RICKARD - Curtin University Australia</i>
	Exi 7	11:50 Study of CIGS Solar Cells by FIB-SEM and Helium Ion Microscopy <i>Fabian PEREZ WILLARD - Carl Zeiss Microscopy GmbH Germany</i>
	12:30	LUNCH + POSTER
	14:00	Pannel Discussion
Life Science	Tuto 3	14:20 Key Aspects of Cryogenic FIB Operations <i>Stephan GERSTL - ScopeMETH Zurich Switzerland</i>
	Exi 8	14:50 Broad Argon beams (BiBs) for high volume 3D EBSD analysis <i>Vincent RICHARD - Ropers Scientific Gatan Evry France</i>
	Talk 12	15:10 Bacterial-host interactions revealed by a robust cryo-focused ion beam milling workflow <i>Joao MEDEIROS - ETH IMBB Zurich Switzerland</i>
	15:30	COFFEE BREAK
FIB dynamics	Tuto 4	16:00 Mitigated Damage FIB Preparation with dynamic BCA Simulation: TRIDYN <i>Jin HUANG - Dresden Center for Nanoanalysis Dresden Germany</i>
	Exi 9	16:30 Optimisation of the FIB Lift-Out Process through the Addition of Analytic Tools <i>John LINDSAY - Oxford Instruments NanoAnalysis High Wycombe UK</i>
	Talk 13	16:50 FIB Patterning Speed Enhancement by Hardmasking and Sketch & Peel to Create Large Area Nanostructures <i>Achim Nadzeyko - Raith GmbH Dortmund Germany</i>
Exi 10	17:10 In situ correlative AFM/SEM analysis of FIB modified surfaces of sensitive samples <i>Jan NEUMAN - NenoVision Brno Czech Republic</i>	
	17:30	Closing